## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | YAMAMICHI ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0042777 A1	04-2002	Yoshida et al.	705/41
*	В	US-6,434,535 B1	08-2002	Kupka et al.	705/24
*	С	US-2003/0018586 A1	01-2003	Krahn, Gerald C.	705/58
*	D	US-2003/0031319 A1	02-2003	Abe et al.	380/232
*	Е	US-2003/0200216 A1	10-2003	Hayes et al.	707/9
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003132425 A	05-2003	Japan	OTSUKA et al.	G07F 17/00
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.